TLVx316

10-MHz, Rail-to-Rail Input/Output, Low-Voltage, 1.8-V CMOS Operational Amplifiers

1 Features

• Unity-Gain Bandwidth: 10 MHz

Low I_Q: 400 μA/ch

Excellent Power-to-Bandwidth Ratio

 Stable I_Q Over Temperature and Supply Range

Wide Supply Range: 1.8 V to 5.5 V
 Low Noise: 12 nV/√Hz at 1 kHz

Low Input Bias Current: ±10 pA

Offset Voltage: ±0.75 mV

Unity-Gain Stable

Internal RFI/EMI Filter

• Extended Temperature Range: -40°C to +125°C

2 Applications

· Battery-Powered Instruments:

Consumer, Industrial, Medical

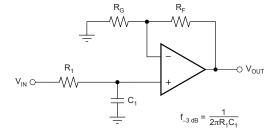
Notebooks, Portable Media Players

Sensor Signal Conditioning

Barcode Scanners

Active Filters

Audio



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$$

Single-Pole, Low-Pass Filter

3 Description

The TLV316 (single), TLV2316 (dual), and TLV4316 (quad) devices comprise a family of general-purpose, low-power operational amplifiers. Features such as rail-to-rail input and output swings, low quiescent current (400 μ A/ch typical) combined with a wide bandwidth of 10 MHz, and very-low noise (12 nV/ $\sqrt{\text{Hz}}$ at 1 kHz) make this family attractive for a variety of applications that require a good balance between cost and performance. The low input bias current supports operational amplifiers that are used in applications with megaohm source impedances.

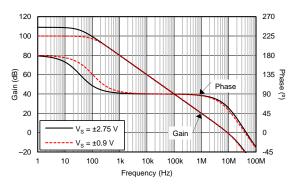
The robust design of the TLVx316 provides ease-ofuse to the circuit designer—a unity-gain stable, integrated RFI/EMI rejection filter, no phase reversal in overdrive condition, and high electrostatic discharge (ESD) protection (4-kV HBM).

These devices are optimized for low-voltage operation as low as 1.8 V (± 0.9 V) and up to 5.5 V (± 2.75 V). This latest addition of low-voltage CMOS operational amplifiers to the portfolio, in conjunction with the TLVx313 and TLVx314 series, offer a family of bandwidth, noise, and power options to meet the needs of a wide variety of applications.

Device Information⁽¹⁾

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TLV316	SC70 (5)	1.25 mm × 2.00 mm
ILVSIO	SOT-23 (5)	1.60 mm × 2.90 mm
TI \ (00.40	VSSOP (8)	3.00 mm × 3.00 mm
TLV2316	SOIC (8)	3.91 mm × 4.90 mm
TLV4316	TSSOP (14)	4.40 mm × 5.00 mm
1LV4310	SOIC (14)	8.65 mm × 3.91 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Low Supply Current (400 µA/Ch) for 10-MHz Bandwidth

Table of Contents

1	Features 1		8.3 Feature Description	14
2	Applications 1		8.4 Device Functional Modes	15
3	Description 1	9	Application and Implementation	16
4	Revision History2		9.1 Application Information	16
5	Device Comparison Table		9.2 System Examples	16
6	Pin Configuration and Functions	10	Power Supply Recommendations	17
7	Specifications		10.1 Input and ESD Protection	17
'	7.1 Absolute Maximum Ratings	11	Layout	18
	7.2 ESD Ratings		11.1 Layout Guidelines	18
	7.3 Recommended Operating Conditions		11.2 Layout Example	18
	7.4 Thermal Information: TLV316	12	Device and Documentation Support	19
	7.5 Thermal Information: TLV2316		12.1 Documentation Support	19
	7.6 Thermal Information: TLV4316		12.2 Related Links	19
	7.7 Electrical Characteristics		12.3 Community Resources	19
	7.8 Typical Characteristics		12.4 Trademarks	19
	7.9 Typical Characteristics		12.5 Electrostatic Discharge Caution	20
8	Detailed Description		12.6 Glossary	20
U	8.1 Overview	13	Mechanical, Packaging, and Orderable	
	8.2 Functional Block Diagram		Information	20

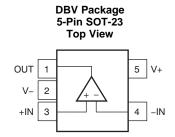
4 Revision History

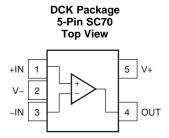
CI	hanges from Original (February 2016) to Revision A	Page
•	Added 14-pin SOIC package information to Device Information table	1
•	Added D package to PW package pinout drawing	5
•	Added D (SOIC) thermal values to Thermal Information: TLV4316 table	<mark>7</mark>

5 Device Comparison Table

	NO. OF			S		
DEVICE	CHANNELS	DBV	DCK	D	DGK	PW
TLV316	1	5	5	_	_	_
TLV2316	2	_	_	8	8	_
TLV4316	4	_	_	14	_	14

6 Pin Configuration and Functions

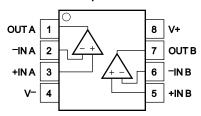




Pin Functions: TLV316

	THIT dilotions. TEVOTO					
PIN		1/0	DESCRIPTION			
NAME	DBV (SOT-23)	DCK (SC70)	1/0	DESCRIPTION		
-IN	4	3	I	Inverting input		
+IN	3	1	I	Noninverting input		
OUT	1	4	0	Output		
V-	2	2	_	Negative (lowest) supply or ground (for single-supply operation)		
V+	5	5	_	Positive (highest) supply		

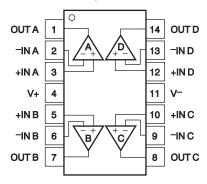
D, DGK Packages 8-Pin SOIC, VSSOP Top View



Pin Functions: TLV2316

F	PIN	1/0	DESCRIPTION	
NO.	NAME	1/0		
2	−IN A	I	Inverting input, channel A	
3	+IN A	I	Noninverting input, channel A	
6	–IN B	I	Inverting input, channel B	
5	+IN B	I	Noninverting input, channel B	
1	OUT A	0	Output, channel A	
7	OUT B	0	Output, channel B	
4	V-	_	Negative (lowest) supply or ground (for single-supply operation)	
8	V+	_	Positive (highest) supply	

D, PW Packages 14-Pin SOIC, TSSOP Top View



Pin Functions: TLV4316

PIN		1/0	DESCRIPTION	
NO.	NAME	I/O	DESCRIPTION	
2	−IN A	1	Inverting input, channel A	
3	+IN A	1	Noninverting input, channel A	
6	−IN B	1	Inverting input, channel B	
5	+IN B	I	Noninverting input, channel B	
9	–IN C	I	Inverting input, channel C	
10	+IN C	I	Noninverting input, channel C	
13	–IN D	I	Inverting input, channel D	
12	+IN D	I	Noninverting input, channel D	
1	OUT A	0	Output, channel A	
7	OUT B	0	Output, channel B	
8	OUT C	0	Output, channel C	
14	OUT D	0	Output, channel D	
11	V-	_	Negative (lowest) supply or ground (for single-supply operation)	
4	V+	_	Positive (highest) supply	

7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature (unless otherwise noted)(1)

			MIN	MAX	UNIT	
Supply voltage				7	V	
	Voltage ⁽²⁾	Common-mode	(V-) - 0.5	(V+) + 0.5		
Signal input pins	voltage (=)	Differential		(V+) - (V-) + 0.2	V	
	Current ⁽²⁾		-10	10	mA	
Output short-circuit (3)			Cont	inuous	mA	
	Specified, T _A		-40	125		
Temperature	Junction, T _J			150	°C	
	Storage, T _{stg}		-65	150		

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 ESD Ratings

over operating free-air temperature range (unless otherwise noted)

			VALUE	UNIT
V	Floatrootatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±4000	\/
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
V_S	Supply voltage	1.8	5.5	V
	Specified temperature range	-40	125	°C

⁽²⁾ Input pins are diode-clamped to the power-supply rails. Current limit input signals that can swing more than 0.5 V beyond the supply rails to 10 mA or less.

⁽³⁾ Short-circuit to ground, one amplifier per package.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

7.4 Thermal Information: TLV316

		TL\	/316	
	THERMAL METRIC ⁽¹⁾	DBV (SOT-23)	DCK (SC70)	UNIT
		5 PINS	5 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	221.7	263.3	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	144.7	75.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	49.7	51.0	°C/W
ΨЈТ	Junction-to-top characterization parameter	26.1	1.0	°C/W
ΨЈВ	Junction-to-board characterization parameter	49.0	50.3	°C/W
R ₀ JC(bot)	Junction-to-case(bottom) thermal resistance	N/A	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics (SPRA953).

7.5 Thermal Information: TLV2316

		TL	TLV2316			
	THERMAL METRIC ⁽¹⁾	D (SOIC)	DGK (VSSOP)	UNIT		
		8 PINS	8 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	127.2	186.6	°C/W		
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	71.6	78.8	°C/W		
$R_{\theta JB}$	Junction-to-board thermal resistance	68.2	107.9	°C/W		
ΨЈТ	Junction-to-top characterization parameter	22.0	15.5	°C/W		
ΨЈВ	Junction-to-board characterization parameter	67.6	106.3	°C/W		
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	N/A	°C/W		

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics (SPRA953).

7.6 Thermal Information: TLV4316

	THERMAL METRIC ⁽¹⁾	PW (TSSOP)	D (SOIC)	UNIT
		14 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	117.2	87.0	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	46.2	44.4	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	58.9	41.7	°C/W
ΨЈТ	Junction-to-top characterization parameter	4.9	11.6	°C/W
ΨЈВ	Junction-to-board characterization parameter	58.3	41.4	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see Semiconductor and IC Package Thermal Metrics (SPRA953).

7.7 Electrical Characteristics

at $T_A = 25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to V_S / 2, $V_{CM} = V_S$ / 2, and $V_{OUT} = V_S$ / 2 (unless otherwise noted); V_S (total supply voltage) = (V+) - (V-) = 1.8 V to 5.5 V

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFFSET	VOLTAGE						
	Innut offect veltere	V _S = 5 V		±0.75	±3	\ /	
V _{os}	Input offset voltage	$V_S = 5 \text{ V}, T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}$			±4.5	mV	
dV _{OS} /dT	Drift	$V_S = 5 \text{ V}, T_A = -40^{\circ}\text{C to } +125^{\circ}\text{C}$		±2		μV/°C	
PSRR	Power-supply rejection ratio	$V_S = 1.8 \text{ V} - 5.5 \text{ V}, V_{CM} = (V-)$		±30	±175	μV/V	
	Channel separation, dc	At dc		100		dB	
INPUT VO	OLTAGE RANGE				'		
V_{CM}	Common-mode voltage range	V _S = 5.5 V	(V-) - 0.2		(V+) + 0.2	V	
		$V_S = 5.5 \text{ V}, (V-) - 0.2 \text{ V} < V_{CM} < (V+) - 1.4 \text{ V}, $ $T_A = -40 ^{\circ}\text{C to } +125 ^{\circ}\text{C}$	72	90		٩D	
CMRR	Common-mode rejection ratio	V _S = 5.5 V, V _{CM} = -0.2 V to 5.7 V, T _A = -40°C to +125°C		75		dB	
INPUT BI	IAS CURRENT						
I _B	Input bias current			±10		pA	
Ios	Input offset current			±10		pA	
NOISE							
En	Input voltage noise (peak-to-peak)	V _S = 5 V, f = 0.1 Hz to 10 Hz		5		μV_{PP}	
e _n	Input voltage noise density	V _S = 5 V, f = 1 kHz		12		nV/√ Hz	
i _n	Input current noise density	f = 1 kHz		1.3		fA/√ Hz	
INPUT IM	MPEDANCE	1					
Z _{ID}	Differential			2 2		10 ¹⁶ Ω pF	
Z _{IC}	Common-mode			2 4		10 ¹¹ Ω pF	
OPEN-LC	OOP GAIN	!					
		$V_S = 5.5 \text{ V}, (V-) + 0.05 \text{ V} < V_O < (V+) - 0.05 \text{ V}, \\ R_L = 10 \text{ k}\Omega$	100	104			
A _{OL}	Open-loop voltage gain	$V_S = 5.5 \text{ V}, (V-) + 0.15 \text{ V} < V_O < (V+) - 0.15 \text{ V}, $ $R_L = 2 \text{ k}\Omega$	104			dB	
FREQUE	NCY RESPONSE						
GBP	Gain bandwidth product	V _S = 5 V, G = +1		10		MHz	
φm	Phase margin	V _S = 5 V, G = +1		60		Degrees	
SR	Slew rate	V _S = 5 V, G = +1		6		V/μs	
t _S	Settling time	To 0.1%, $V_S = 5 \text{ V}$, 2-V step , $G = +1$, $C_L = 100 \text{ pF}$		1		μS	
t _{OR}	Overload recovery time	$V_S = 5 \text{ V}, V_{IN} \times \text{gain} = V_S$		0.8		μS	
THD + N	Total harmonic distortion + noise ⁽¹⁾	$V_S = 5 \text{ V}, V_O = 0.5 \text{ V}_{RMS}, G = +1, f = 1 \text{ kHz}$		0.008%			
OUTPUT					'		
	Voltage output swing from supply	$V_S = 1.8 \text{ V to } 5.5 \text{ V}, R_L = 10 \text{ k}\Omega,$			35		
Vo	rails	$V_S = 1.8 \text{ to } 5.5 \text{ V}, R_L = 2 \text{ k}\Omega,$	125			mV	
I _{SC}	Short-circuit current	V _S = 5 V		±50		mA	
	Open-loop output impedance	V _S = 5 V, f = 10 MHz		250		Ω	
Zo							
Z _O	SUPPLY						
POWER S			1.8		5.5	V	
POWER S	Specified voltage range	V _S = 5 V, I _Ω = 0 mA, T _Δ = -40°C to 125°C	1.8	400			
POWER S	Specified voltage range Quiescent current per amplifier	$V_S = 5 \text{ V}, I_O = 0 \text{ mA}, T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	1.8	400	5.5 575	V µA	
POWER S	Specified voltage range Quiescent current per amplifier	$V_S = 5 \text{ V}, I_O = 0 \text{ mA}, T_A = -40^{\circ}\text{C to } 125^{\circ}\text{C}$	1.8	400			

⁽¹⁾ Third-order filter; bandwidth = 80 kHz at -3 dB.

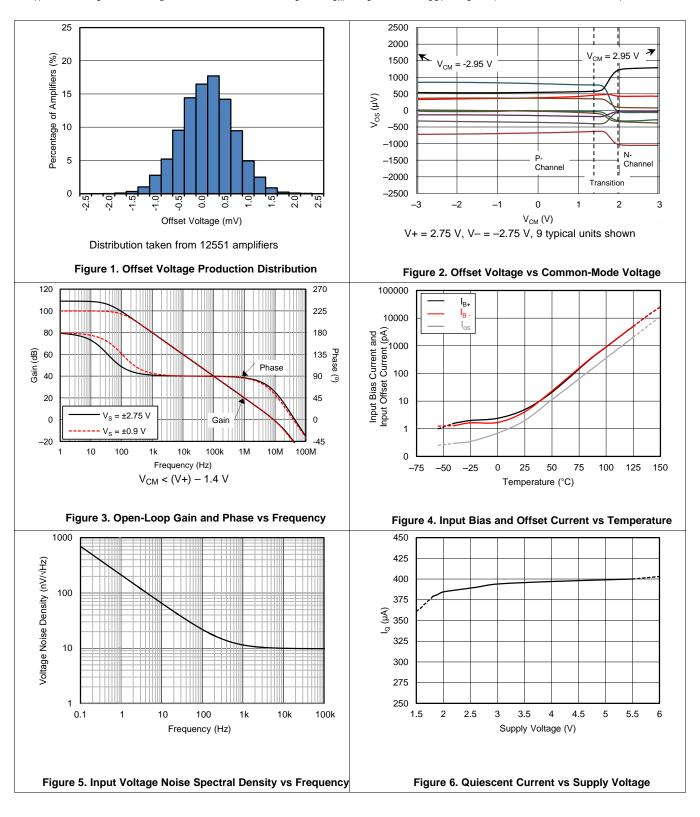
7.8 Typical Characteristics

Table 1. Table of Graphs

TITLE	FIGURE
Offset Voltage Production Distribution	Figure 1
Offset Voltage vs Common-Mode Voltage	Figure 2
Open- Loop Gain and Phase vs Frequency	Figure 3
Input Bias and Offset Current vs Temperature	Figure 4
Input Voltage Noise Spectral Density vs Frequency	Figure 5
Quiescent Current vs Supply Voltage	Figure 6
Small-Signal Overshoot vs Load Capacitance	Figure 7
No Phase Reversal	Figure 8
Small-Signal Step Response	Figure 9
Large-Signal Step Response	Figure 10
Short-Circuit Current vs Temperature	Figure 11
Electromagnetic Interference Rejection Ratio Referred to Noninverting Input vs Frequency	Figure 12
Channel Separation vs Frequency	Figure 13

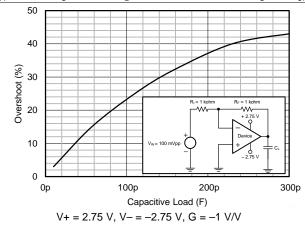
7.9 Typical Characteristics

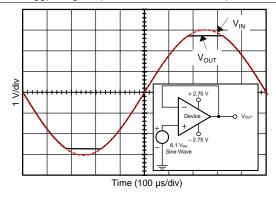
at T_A = 25°C, V_S = 5.5 V, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_S / 2, and V_{OUT} = V_S / 2 (unless otherwise noted)



Typical Characteristics (continued)

at $T_A = 25$ °C, $V_S = 5.5$ V, $R_L = 10$ k Ω connected to $V_S / 2$, $V_{CM} = V_S / 2$, and $V_{OUT} = V_S / 2$ (unless otherwise noted)

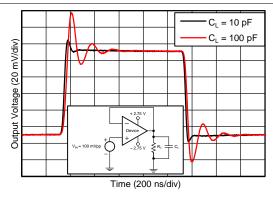




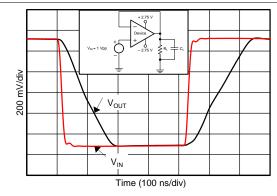
V+ = 2.75 V, V- = -2.75 V

Figure 7. Small-Signal Overshoot vs Load Capacitance





V+ = 2.75 V, V- = -2.75 V, G = 1 V/V



 $V+ = 2.75 \text{ V}, V- = -2.75 \text{ V}, C_L = 100 \text{ pF}, G = 1 \text{ V/V}$



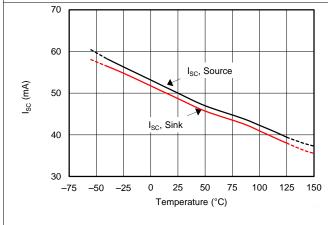


Figure 11. Short-Circuit Current vs Temperature



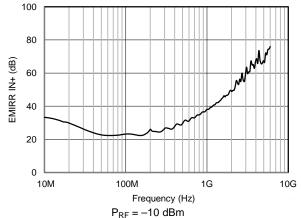
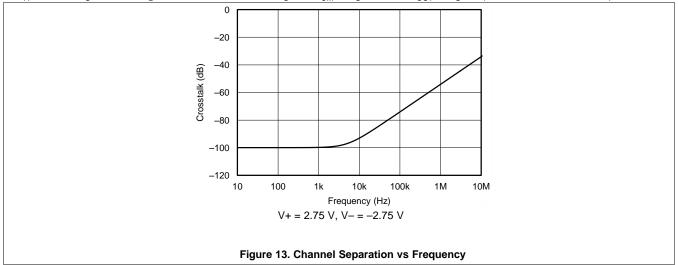


Figure 12. Electromagnetic Interference Rejection Ratio Referred to Noninverting Input vs Frequency

Typical Characteristics (continued)

at $T_A = 25$ °C, $V_S = 5.5$ V, $R_L = 10$ k Ω connected to V_S / 2, $V_{CM} = V_S$ / 2, and $V_{OUT} = V_S$ / 2 (unless otherwise noted)



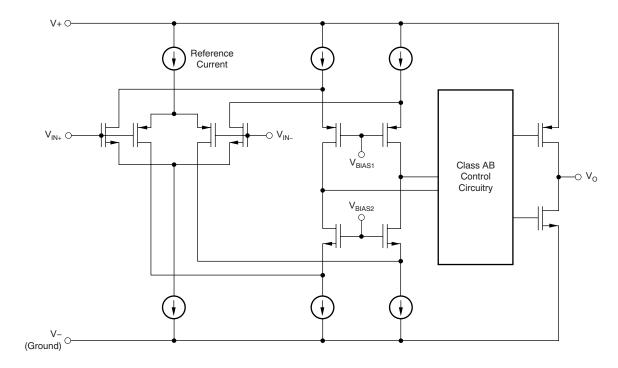
8 Detailed Description

8.1 Overview

The TLVx316 is a family of low-power, rail-to-rail input and output operational amplifiers. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and are suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving ≤ 10 -k Ω loads connected to any point between V+ and ground. The input common-mode voltage range includes both rails and allows the TLVx316 to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes them suitable for driving sampling analog-to-digital converters (ADCs).

The TLVx316 features 10-MHz bandwidth and 6-V/ μ s slew rate with only 400- μ A supply current per channel, providing good ac performance at very-low power consumption. DC applications are well served with a very-low input noise voltage of 12 nV/ $\sqrt{\text{Hz}}$ at 1 kHz, low input bias current (5 pA), and an input offset voltage of 0.5 mV (typical).

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Operating Voltage

The TLVx316 operational amplifiers are fully specified and ensured for operation from 1.8 V to 5.5 V. In addition, many specifications apply from –40°C to +125°C. Parameters that vary significantly with operating voltages or temperature are illustrated in the *Typical Characteristics* section.

8.3.2 Rail-to-Rail Input

The input common-mode voltage range of the TLVx316 extends 200 mV beyond the supply rails for supply voltages greater than 2.5 V. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair; see the *Functional Block Diagram* section. The N-channel pair is active for input voltages close to the positive rail, typically (V+) - 1.4 V to 200 mV above the positive supply, whereas the P-channel pair is active for inputs from 200 mV below the negative supply to approximately (V+) - 1.4 V. There is a small transition region, typically (V+) - 1.2 V to (V+) - 1 V, in which both pairs are on. This 200-mV transition region can vary up to 200 mV with process variation. Thus, the transition region (both stages on) can range from (V+) - 1.4 V to (V+) - 1.2 V on the low end, up to (V+) - 1 V to (V+) - 0.8 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD can be degraded compared to device operation outside this region.

8.3.3 Rail-to-Rail Output

Designed as a low-power, low-voltage operational amplifier, the TLVx316 delivers a robust output drive capability. A class AB output stage with common-source transistors is used to achieve full rail-to-rail output swing capability. For resistive loads of 10 k Ω , the output swings typically to within 30 mV of either supply rail regardless of the power-supply voltage applied. Different load conditions change the ability of the amplifier to swing close to the rails; see typical characteristic graph *Output Voltage Swing vs Output Current* ().

8.3.4 Common-Mode Rejection Ratio (CMRR)

CMRR for the TLVx316 is specified in two ways so the best match for a given application can be selected. First, the *Electrical Characteristics* table provides the CMRR of the device in the common-mode range below the transition region [$V_{CM} < (V+) - 1.4 V$]. This specification is the best indicator of device capability when the application requires using one of the differential input pairs. Second, the CMRR over the entire common-mode range is specified at $V_{CM} = -0.2 V$ to 5.7 V for $V_{S} = 5.5 V$. This last value includes the variations through the transition region.

8.3.5 Capacitive Load and Stability

The TLVx316 is designed to be used in applications where driving a capacitive load is required. As with all operational amplifiers, there may be specific instances where the TLVx316 can become unstable. The particular operational amplifier circuit configuration, layout, gain, and output loading are some of the factors to consider when establishing whether or not an amplifier is stable in operation. An operational amplifier in the unity-gain (1 V/V) buffer configuration that drives a capacitive load exhibits a greater tendency to be unstable than an amplifier operated at a higher noise gain. The capacitive load, in conjunction with the operational amplifier output resistance, creates a pole within the feedback loop that degrades the phase margin. The degradation of the phase margin increases when the capacitive loading increases. For a conservative best practice, designing for 25% overshoot (40° phase margin) provides improved stability over process variations. The equivalent series resistance (ESR) of some very-large capacitors (C_L greater than 1 μ F) is sufficient to alter the phase characteristics in the feedback loop such that the amplifier remains stable. Increasing the amplifier closed-loop gain allows the amplifier to drive increasingly larger capacitance. This increased capability is evident when observing the overshoot response of the amplifier at higher voltage gains. See typical characteristic graph, Small-Signal Overshoot vs Capacitive Load (Figure 7, G = -1 V/V).

Feature Description (continued)

One technique for increasing the capacitive load drive capability of the amplifier operating in a unity-gain configuration is to insert a small resistor (typically 10 Ω to 20 Ω) in series with the output, as shown in Figure 14. This resistor significantly reduces the overshoot and ringing associated with large capacitive loads. One possible problem with this technique, however, is that a voltage divider is created with the added series resistor and any resistor connected in parallel with the capacitive load. The voltage divider introduces a gain error at the output that reduces the output swing.

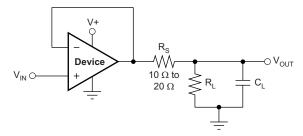


Figure 14. Improving Capacitive Load Drive

8.3.6 EMI Susceptibility and Input Filtering

Operational amplifiers vary with regard to the susceptibility of the device to electromagnetic interference (EMI). If conducted EMI enters the operational amplifier, the dc offset measured at the amplifier output can shift from its nominal value when EMI is present. This shift is a result of signal rectification associated with the internal semiconductor junctions. Although all operational amplifier pin functions can be affected by EMI, the signal input pins are likely to be the most susceptible. The TLVx316 operational amplifier family incorporates an internal input low-pass filter that reduces the amplifier response to EMI. This filter provides both common-mode and differential-mode filtering. The filter is designed for a cutoff frequency of approximately 80 MHz (–3 dB), with a roll-off of 20 dB per decade.

The immunity of an operational amplifier can be accurately measured and quantified over a broad frequency spectrum extending from 10 MHz to 6 GHz. The EMI rejection ratio (EMIRR) metric allows operational amplifiers to be directly compared by the EMI immunity. Figure 12 illustrates the results of this testing on the TLVx316. Detailed information can be found in *EMI Rejection Ratio of Operational Amplifiers* (SBOA128), available for download from www.ti.com.

8.3.7 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from a saturated state to a linear state. The output devices of the operational amplifier enter a saturation region when the output voltage exceeds the rated operating voltage, either because of the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return back to the linear state. After the charge carriers return back to the linear state, the device begins to slew at the specified slew rate. Thus, the propagation delay in case of an overload condition is the sum of the overload recovery time and the slew time. The overload recovery time for the TLVx316 is approximately 300 ns.

8.4 Device Functional Modes

The TLVx316 have a single functional mode. These devices are powered on as long as the power-supply voltage is between 1.8 V (± 0.9 V) and 5.5 V (± 2.75 V).

9 Application and Implementation

NOTE

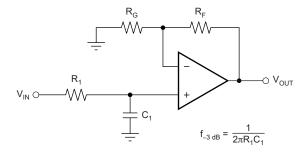
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TLV316, TLV2316, and TLV4316 are powered on when the supply is connected. The devices can be operated as a single-supply operational amplifier or a dual-supply amplifier, depending on the application.

9.2 System Examples

When receiving low-level signals, the device often requires limiting the bandwidth of the incoming signals into the system. The simplest way to establish this limited bandwidth is to place an RC filter at the noninverting pin of the amplifier, as shown in Figure 15.



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$$

Figure 15. Single-Pole, Low-Pass Filter

If even more attenuation is needed, the device requires a multiple-pole filter. The Sallen-Key filter can be used for this task, as shown in Figure 16. For best results, the amplifier must have a bandwidth that is eight to ten times the filter frequency bandwidth. Failure to follow this guideline can result in a phase shift of the amplifier.

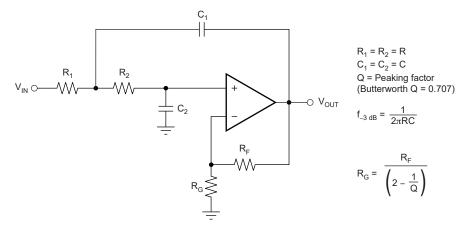


Figure 16. Two-Pole, Low-Pass, Sallen-Key Filter

10 Power Supply Recommendations

The TLVx316 is specified for operation from 1.8 V to 5.5 V (±0.9 V to ±2.75 V); many specifications apply from –40°C to +125°C. *Typical Characteristics* presents parameters that can exhibit significant variance with regard to operating voltage or temperature.

CAUTION

Supply voltages larger than 7 V can permanently damage the device (see the *Absolute Maximum Ratings* table).

Place 0.1- μ F bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see *Layout Guidelines*.

10.1 Input and ESD Protection

The TLVx316 incorporates internal ESD protection circuits on all pins. For input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA, as stated in the *Absolute Maximum Ratings* table. Figure 17 shows how a series input resistor can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and its value must be kept to a minimum in noise-sensitive applications.

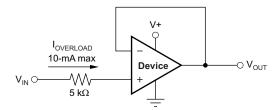


Figure 17. Input Current Protection

11 Layout

11.1 Layout Guidelines

For best operational performance of the device, use good PCB layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and the
 operational amplifier. Bypass capacitors reduce the coupled noise by providing low-impedance power
 sources local to the analog circuitry.
 - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of the circuitry is one of the simplest and most
 effective methods of noise suppression. One or more layers on multilayer PCBs are typically devoted to
 ground planes. A ground plane helps distribute heat and reduces EMI noise pickup. Take care to
 physically separate digital and analog grounds, paying attention to the flow of the ground current. For
 more detailed information, see, Circuit Board Layout Techniques (SLOA089).
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace perpendicularly is much better than crossing in parallel with the noisy trace.
- Place the external components as close to the device as possible. Keeping RF and RG close to the inverting input minimizes parasitic capacitance, as shown in *Layout Example*.
- Keep the length of input traces as short as possible. Remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly
 reduce leakage currents from nearby traces that are at different potentials.

11.2 Layout Example

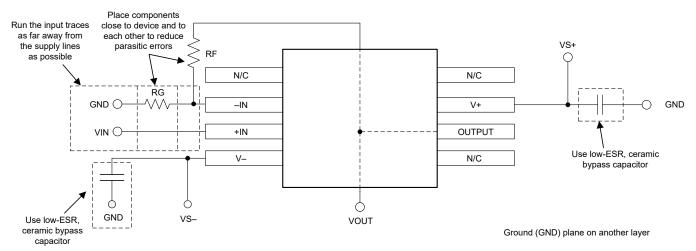


Figure 18. Operational Amplifier Board Layout for a Noninverting Configuration

12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

TLVx313 Low-Power, Rail-to-Rail In/Out, 500-μV Typical Offset, 1-MHz Operational Amplifier for Cost-Sensitive Systems (SBOS753).

TLVx314 3-MHz, Low-Power, Internal EMI Filter, RRIO, Operational Amplifier (SBOS754).

EMI Rejection Ratio of Operational Amplifiers (SBOA128).

QFN/SON PCB Attachment (SLUA271).

Quad Flatpack No-Lead Logic Packages (SCBA017).

Circuit Board Layout Techniques (SLOA089).

Single-Ended Input to Differential Output Conversion Circuit Reference Design (TIPD131).

12.2 Related Links

Table 2 lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
TLV316	Click here	Click here	Click here	Click here	Click here
TLV2316	Click here	Click here	Click here	Click here	Click here
TLV4316	Click here	Click here	Click here	Click here	Click here

Table 2. Related Links

12.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.4 Trademarks

E2E is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TLV2316IDGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	12X6	Samples
TLV2316IDGKT	ACTIVE	VSSOP	DGK	8	250	RoHS & Green	NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	12X6	Samples
TLV2316IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	V2316	Samples
TLV316IDBVR	ACTIVE	SOT-23	DBV	5	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	12C	Samples
TLV316IDBVT	ACTIVE	SOT-23	DBV	5	250	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	12C	Samples
TLV316IDCKR	ACTIVE	SC70	DCK	5	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	12D	Samples
TLV316IDCKT	ACTIVE	SC70	DCK	5	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	12D	Samples
TLV4316IDR	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	T4316D	Samples
TLV4316IPWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	TLV4316	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

PACKAGE OPTION ADDENDUM

10-Dec-2020

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

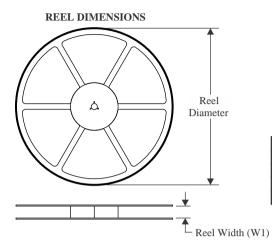
OTHER QUALIFIED VERSIONS OF TLV2316, TLV316, TLV4316:

Automotive: TLV2316-Q1, TLV316-Q1, TLV4316-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

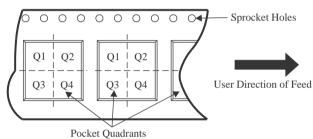
TAPE AND REEL INFORMATION



TAPE DIMENSIONS KO P1 BO BO Cavity AO

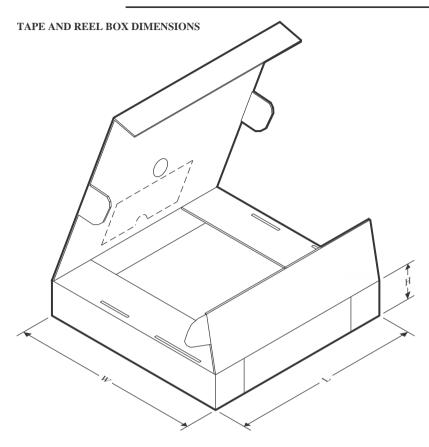
A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV2316IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV2316IDGKT	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV2316IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLV316IDBVR	SOT-23	DBV	5	3000	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
TLV316IDBVT	SOT-23	DBV	5	250	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
TLV316IDCKR	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TLV316IDCKT	SC70	DCK	5	250	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
TLV4316IDR	SOIC	D	14	2500	330.0	16.4	6.5	9.0	2.1	8.0	16.0	Q1
TLV4316IPWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

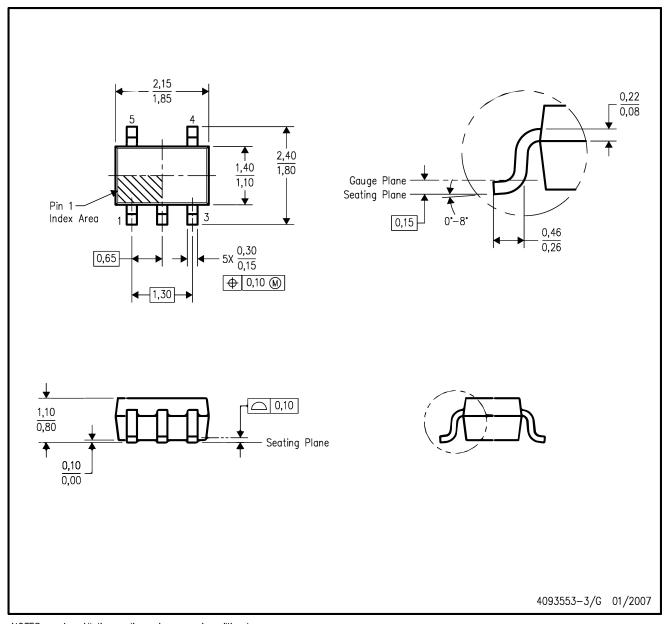


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV2316IDGKR	VSSOP	DGK	8	2500	366.0	364.0	50.0
TLV2316IDGKT	VSSOP	DGK	8	250	366.0	364.0	50.0
TLV2316IDR	SOIC	D	8	2500	356.0	356.0	35.0
TLV316IDBVR	SOT-23	DBV	5	3000	180.0	180.0	18.0
TLV316IDBVT	SOT-23	DBV	5	250	180.0	180.0	18.0
TLV316IDCKR	SC70	DCK	5	3000	180.0	180.0	18.0
TLV316IDCKT	SC70	DCK	5	250	180.0	180.0	18.0
TLV4316IDR	SOIC	D	14	2500	340.5	336.1	32.0
TLV4316IPWR	TSSOP	PW	14	2000	356.0	356.0	35.0

DCK (R-PDSO-G5)

PLASTIC SMALL-OUTLINE PACKAGE

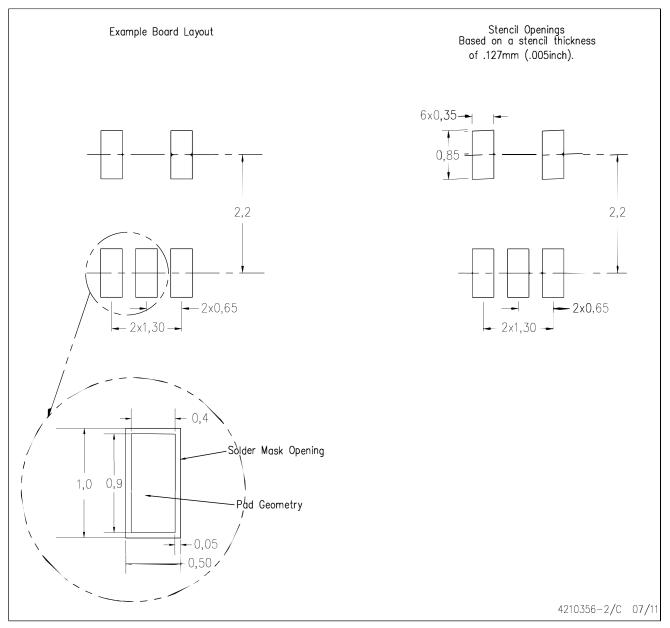


NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
- D. Falls within JEDEC MO-203 variation AA.

DCK (R-PDSO-G5)

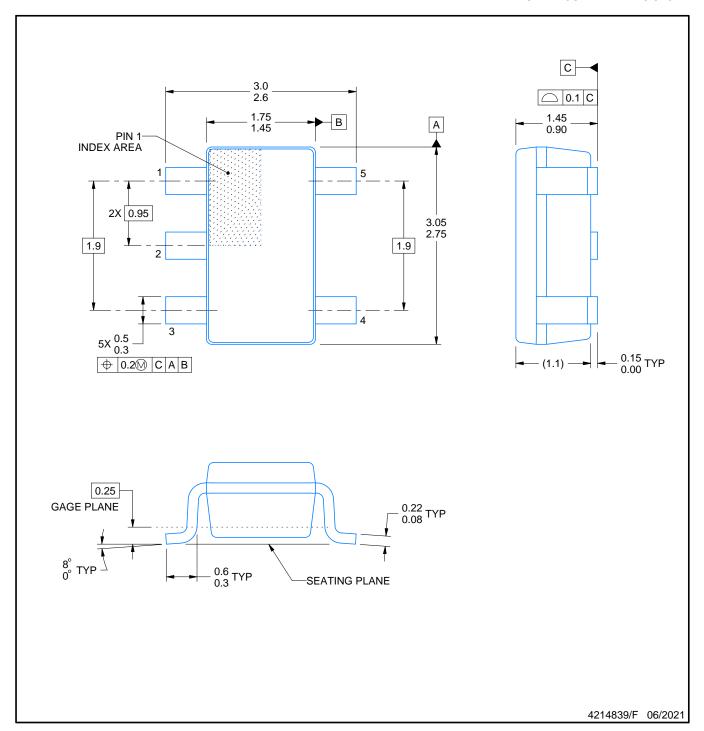
PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



SMALL OUTLINE TRANSISTOR



- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. Reference JEDEC MO-178.

- 4. Body dimensions do not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.25 mm per side.

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

SMALL OUTLINE TRANSISTOR



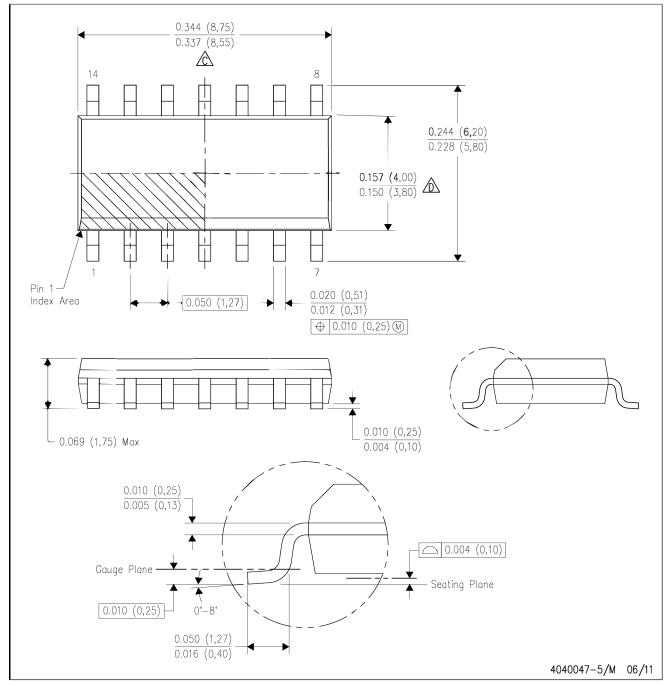
NOTES: (continued)

^{7.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

^{8.} Board assembly site may have different recommendations for stencil design.

D (R-PDSO-G14)

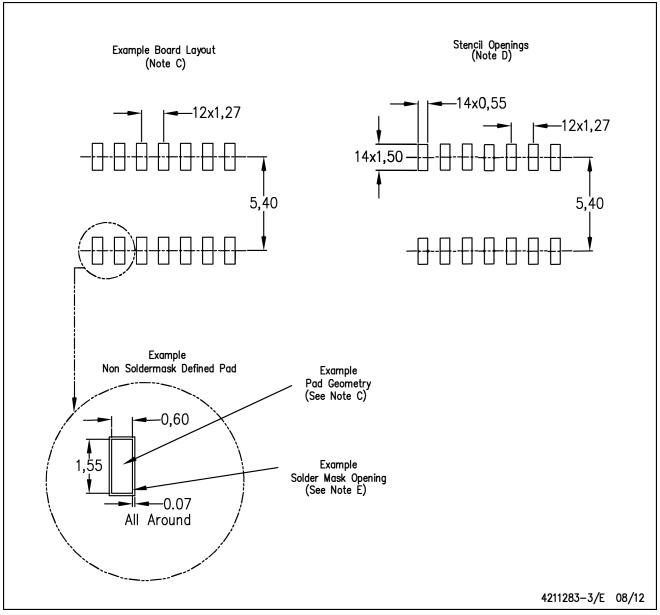
PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AB.

D (R-PDSO-G14)

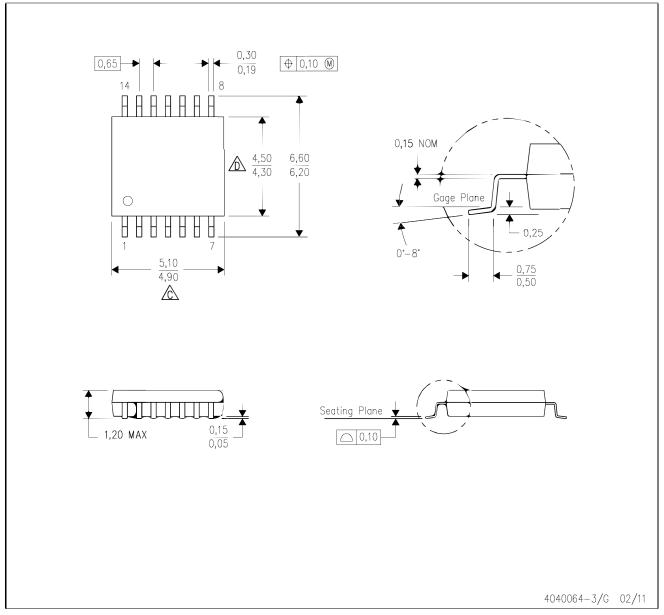
PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

PW (R-PDSO-G14)

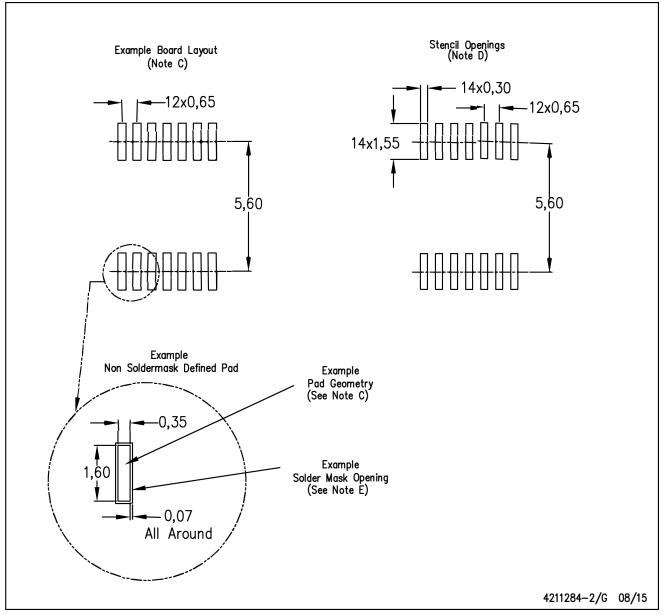
PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153

PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.

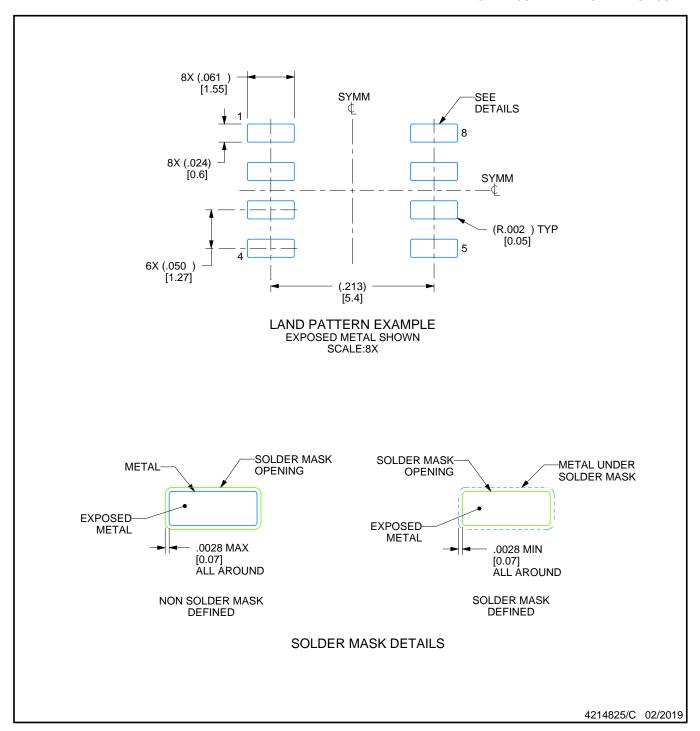


SMALL OUTLINE INTEGRATED CIRCUIT



- 1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

SMALL OUTLINE INTEGRATED CIRCUIT

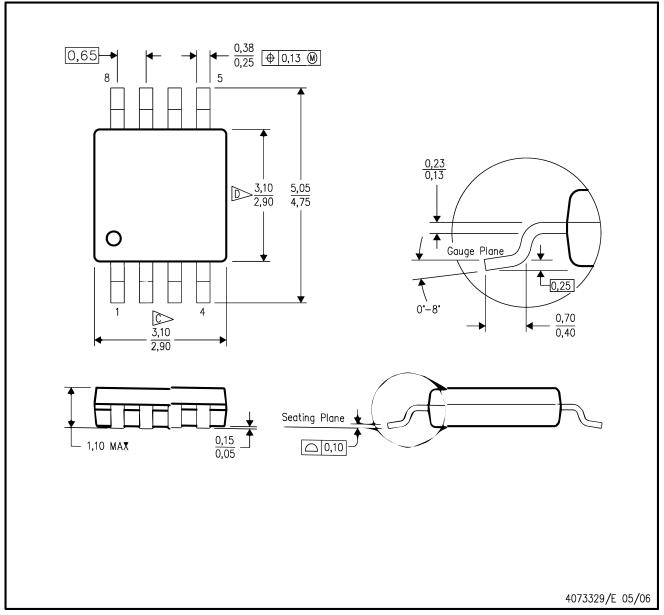


NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.

DGK (S-PDSO-G8)

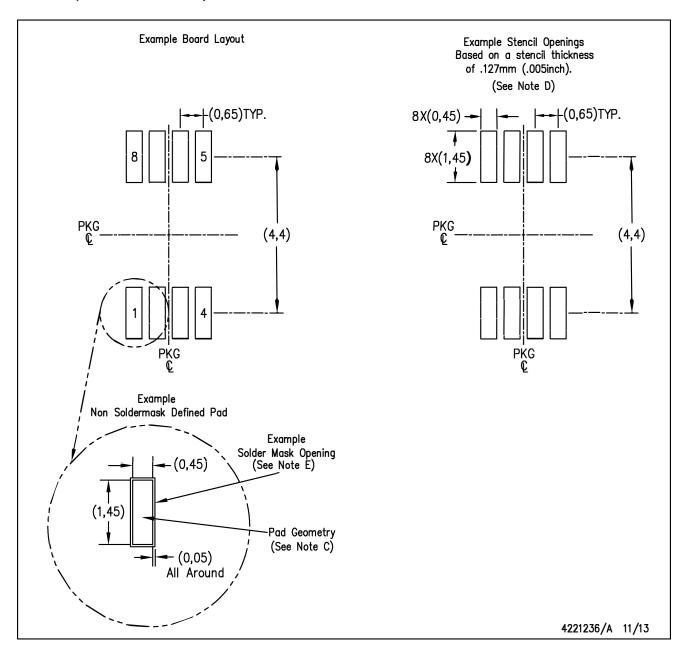
PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.

DGK (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.